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(12) **United States Design Patent**
Brekke et al.

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(54) **MULTIPROBE CIRCUIT TESTER**

(71) Applicant: **SNAP-ON INCORPORATED**, Kenosha, WI (US)

(72) Inventors: **David F. Brekke**, Franksville, WI (US); **Michael G. Holden**, Milwaukee, WI (US); **Wayne Russel**, Ontario, CA (US); **Joshua Carton**, Wilmington, CA (US)

(73) Assignee: **Snap-on Incorporated**, Kenosha, WI (US)

(**) Term: **15 Years**

(21) Appl. No.: **29/606,615**

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(51) **LOC (11) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/78**

(58) **Field of Classification Search**
USPC D10/78
CPC G01R 1/06788; G01R 1/22; G01R 1/04; G01R 15/125; G01R 15/181; G01R 15/186; G01R 15/12; G01R 15/04; G01R 15/06; G01R 19/2503; G01R 1/20; G01R 1/203; G01R 1/206; G01R 1/24; G01R 1/26; G01R 31/3278; G01D 11/24; G01D 11/245; G01D 11/26; G06F 17/00
See application file for complete search history.

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Primary Examiner — Antoine D Davis
(74) *Attorney, Agent, or Firm* — Seyfarth Shaw LLP

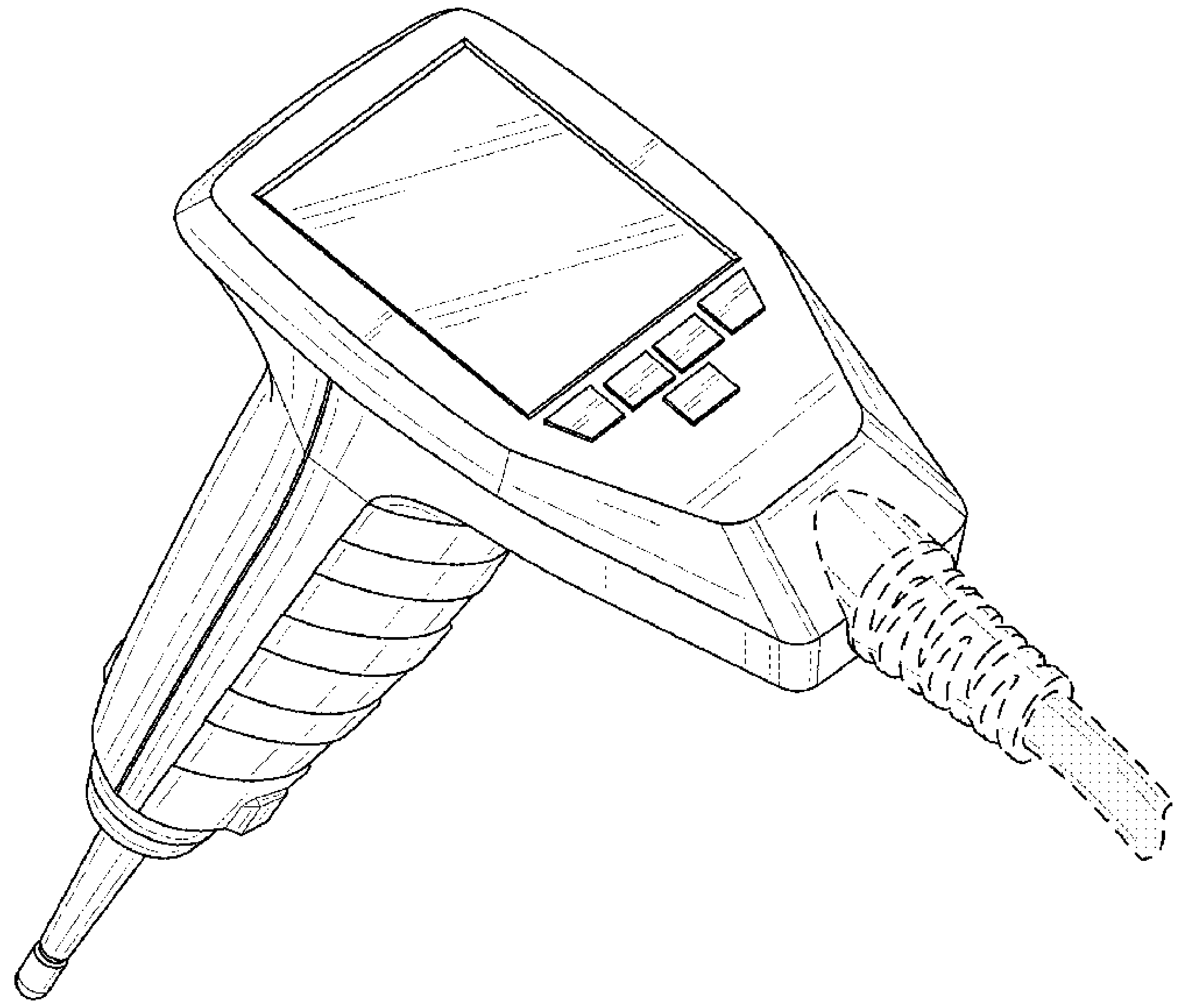
(57) **CLAIM**

The ornamental design for the multiprobe circuit tester, as shown and described.

DESCRIPTION

FIG. **1** is a top perspective view of an embodiment of the multiprobe circuit tester;
FIG. **2** is a first side view of the multiprobe circuit tester;
FIG. **3** is a second side view of the multiprobe circuit tester;
FIG. **4** is a third side view of the multiprobe circuit tester;
FIG. **5** is a fourth side view of the multiprobe circuit tester;
FIG. **6** is a top plan view of the multiprobe circuit tester; and,
FIG. **7** is a bottom plan view of the multiprobe circuit tester.
Any components in the appended drawings shown in broken lines are for illustrative purposes only and form no part of the claimed design or a specified embodiment thereof.

1 Claim, 5 Drawing Sheets



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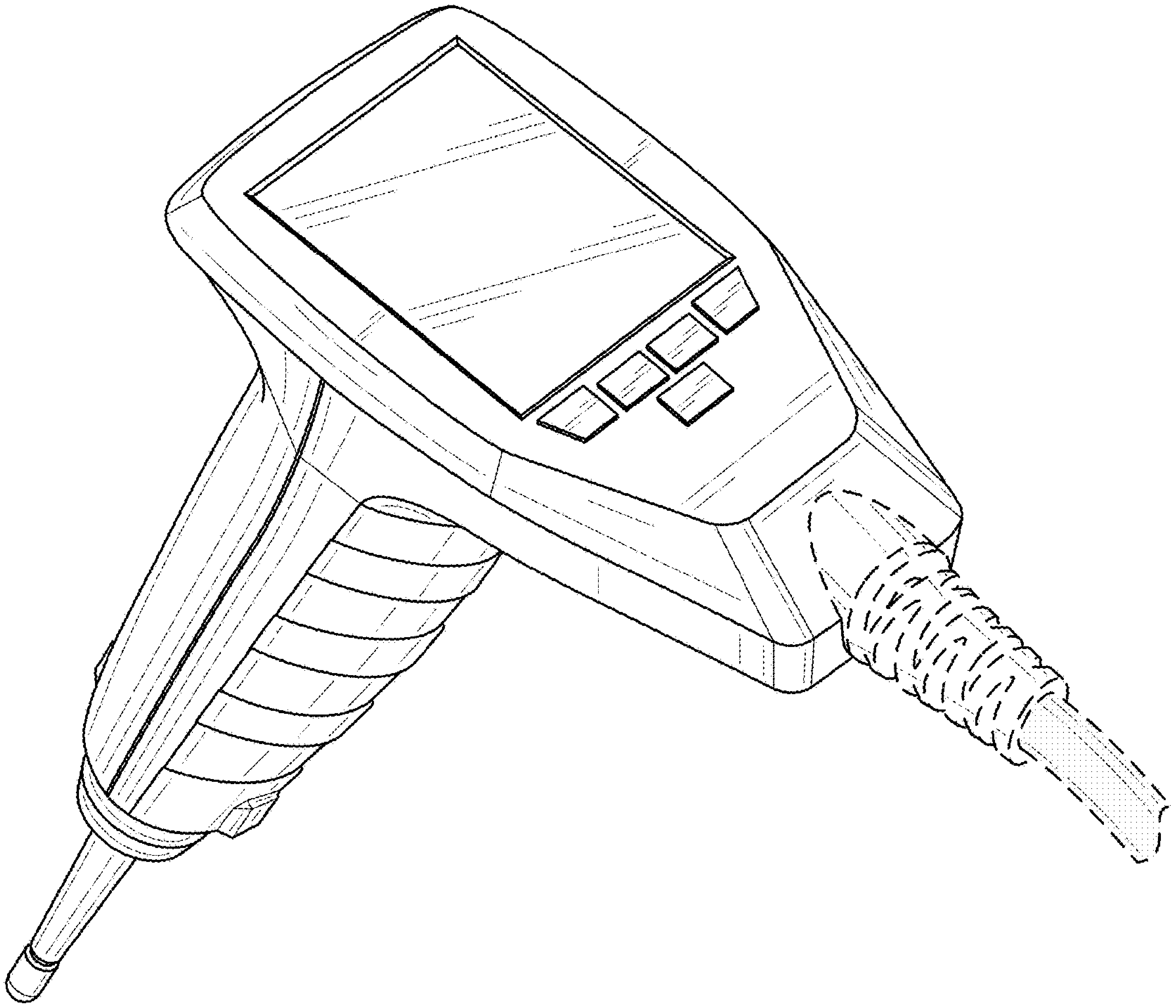

FIG. 1

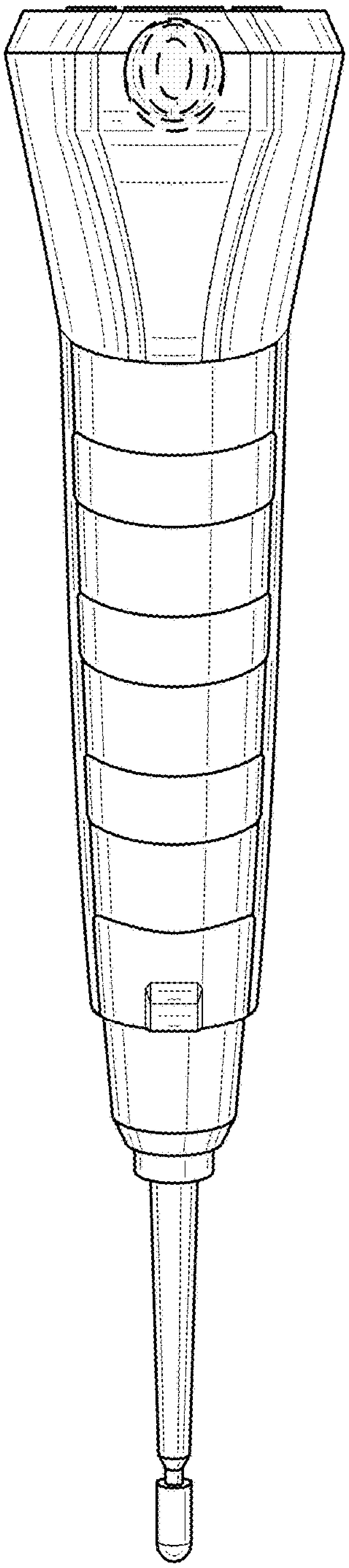

FIG. 2

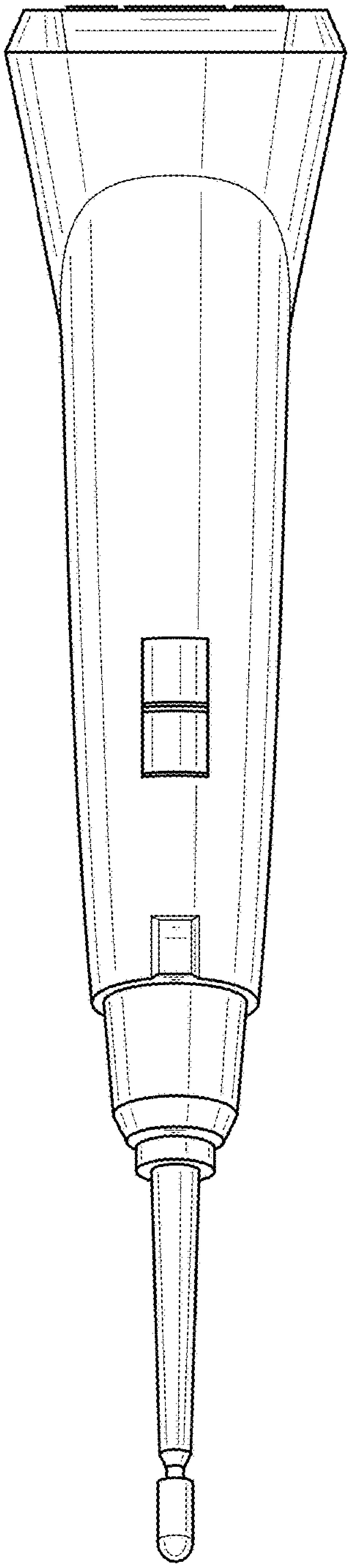

FIG. 3

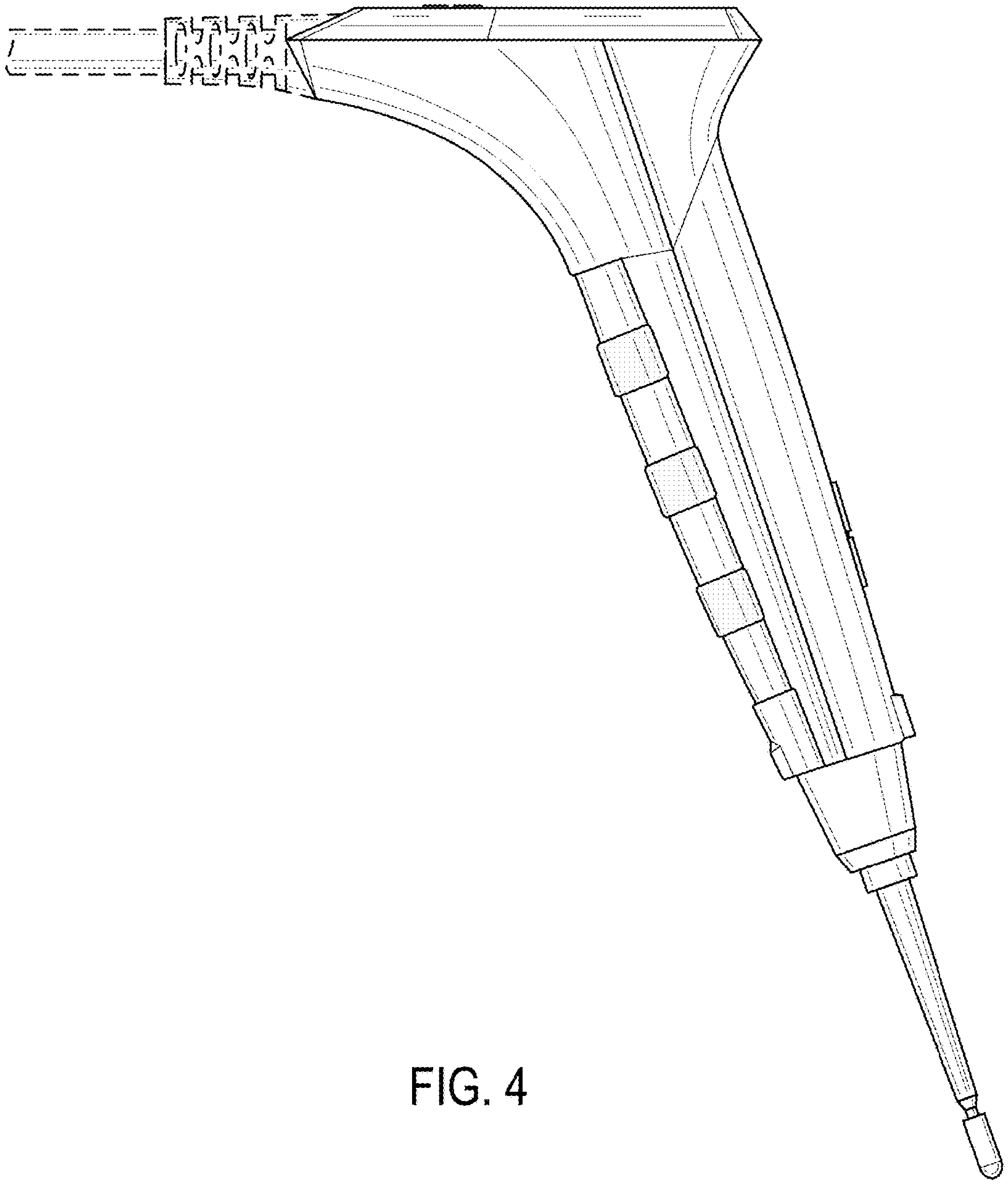

FIG. 4

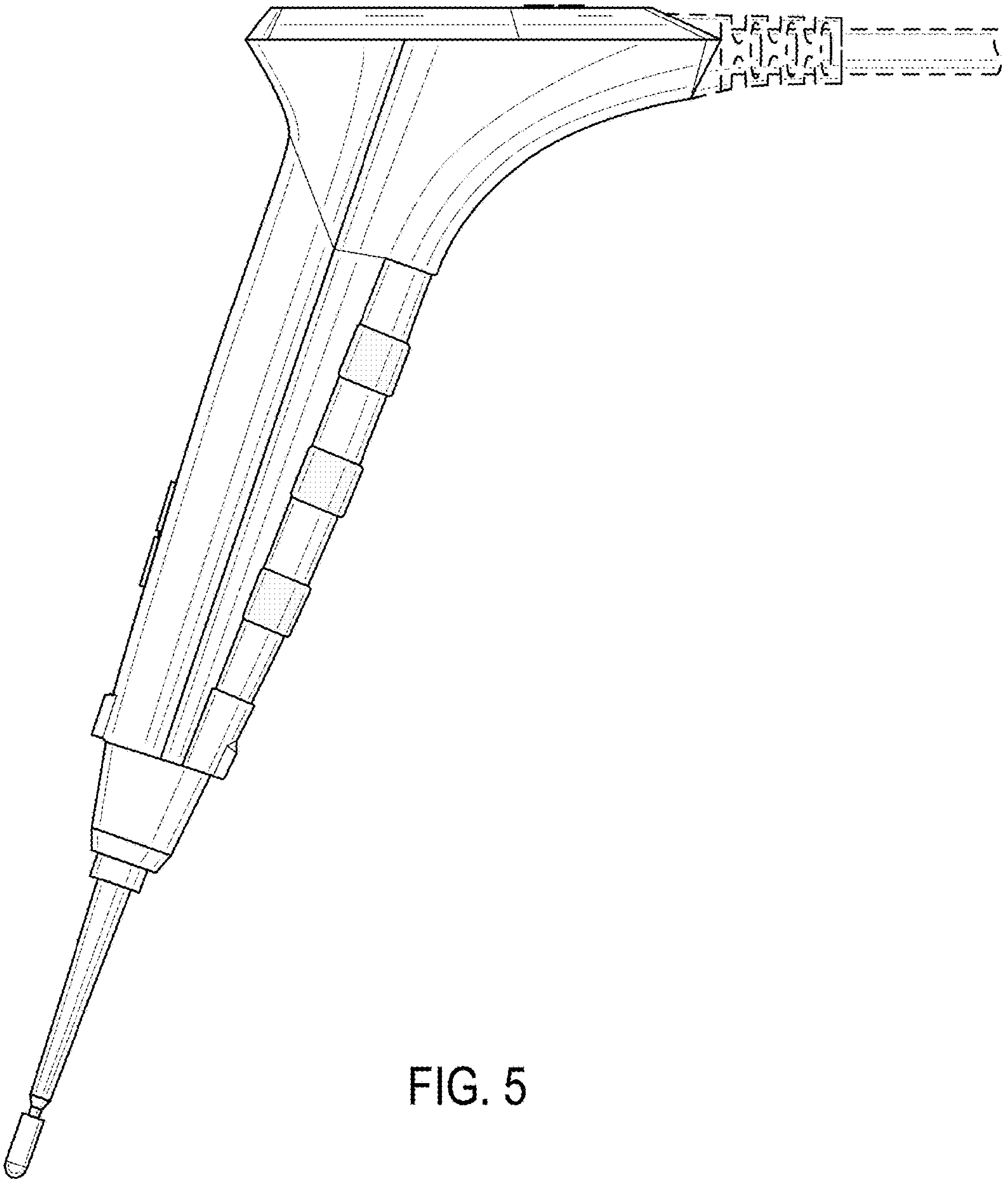

FIG. 5

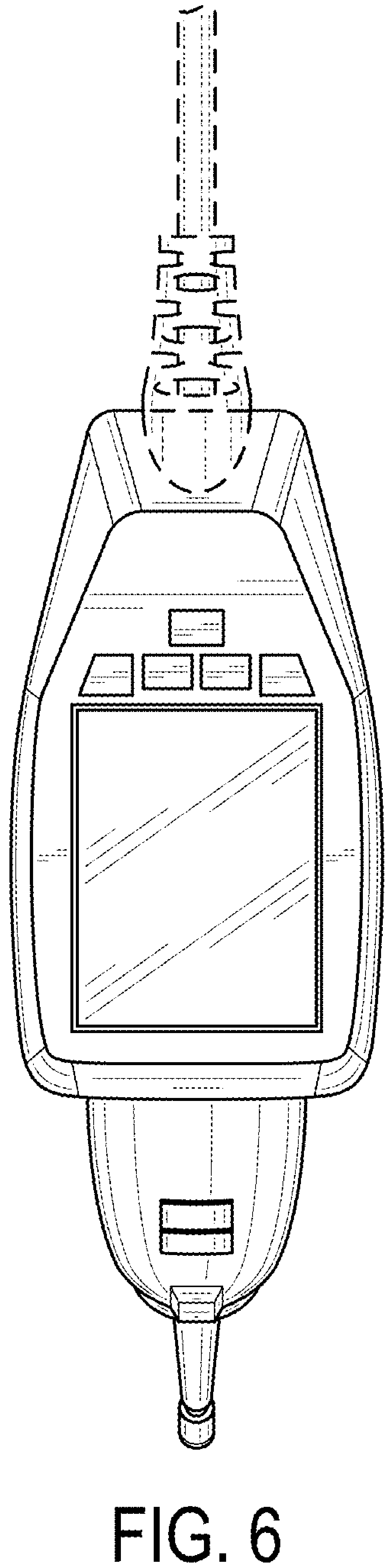

FIG. 6

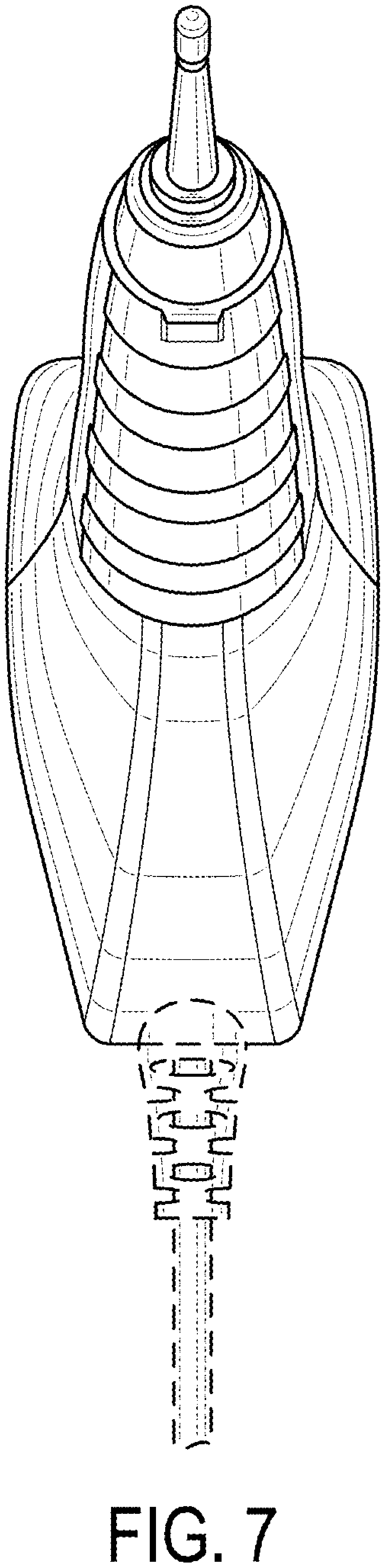

FIG. 7